

Product Change Notice (PCN)

Subject: Add SFA, Korea as Alternate Test Location

Publication Date: 11/2/2023

Effective Date: 2/1/2024

Revision Description:

Initial Release

Description of Change:

Renesas is adding SFA, Korea as an alternate Test Location for the select part# that is currently tested at Sigurd, Taiwan.

This change will allow flexibility to ship from either facilities and will provide the increased capacity, flexibility and shorter lead time to meet market demand. There is no change in the Test processing flows. Load boards and test programs are the same at all the qualified facilities. Renesas has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

Affected Product List: RA9530TRXZOGBM#HCO

Reason for Change:

To provide dual source to secure business continuity.

Impact on Fit, Form, Function, Quality & Reliability:

The change will have no impact on the form, fit, function, quality, reliability and environmental compliance of the products.

Product Identification:

Traceability to the test location is available on request.

Qualification Status: Electrical characterization completed successfully. Refer Appendix A

Sample Availability Date: 11/2/2023

Device Material Declaration: Not applicable

Note:

1. Acknowledgement must be received by Renesas within 30 days or Renesas will consider the change as approved.
2. If timely acknowledgement is provided by Customer, then Customer shall have 90 days from the date of receipt of this PCN to make any objections to this PCN. If Customer fails to make objections to this PCN within 90 days of the receipt of the PCN then Renesas will consider the PCN changes as approved.
3. If customer cannot accept the PCN then customer must provide Renesas with a last time buy demand and purchase order.

For additional information regarding this notice, please contact idt-pcn@lm.renesas.com

Appendix A - Electrical Test Characterization Results
Qual Vehicle: RA9530TRXZ0GBM

Sample size: 16 diced electrically good units tested by hand test.
 One correlation wafer (DPW = 3018) sorted by prober.
 One pilot lot (25 wafers, 75432 dies) sorted by prober.

| Descriptions | Existing Test (Sigurd, Taiwan) | Alternate Test (SFA, Korea) |
|--------------------------------------|---|---|
| Tester Platform | PS1600 | PS1600 |
| Loadboard | IDT-TCTR X CP2-16-Site-S93K-Load board_Rev1 | IDT-TCTR X CP2-16-Site-S93K-Load board_Rev1 |
| Test Program | RA9530-0_BO_CSP_x16_.tp | RA9530-0_BO_CSP_x16_.tp |
| Test Site | 16 | 16 |
| Test Temperature | 25°C | 25°C |
| Test Correlation Results | Passed | Passed |
| Number of Good Units | 16 units | 16 units |
| Number of Loop Test | 10 | 10 |
| Number of Test Appraisers | 16 | 16 |
| 16 good units datalog correlation | Passed | Passed |
| Correlation Wafer Results | Passed | Passed |
| Corr Yield, Pareto and Distribution | Passed | Passed |
| Pilot Yield, Pareto and Distribution | Passed | Passed |